

NANOTS2015 Time Table

11 (Wed)	AM	Life Hall (5F)	Process Evaluation Techniques: Metrology and Inspection I 9:15-10:35	Authors Corner 10:35-10:55	Process Evaluation Techniques: Metrology and Inspection II 10:55-12:10		Break (Hitachi High-Technologies Luncheon Seminar) 12:30-13:50
		Senri Room (6F)					Authors Corner 12:10-12:30
	PM	Life Hall (5F)	Invited Talk 13:50-14:50		Power Device Analysis I 15:10-16:25		Power Device Analysis II 16:45-18:00
		Senri Room (6F)		Break 14:50-15:10		Authors Corner 16:25-16:45	Authors Corner 18:00-18:20

12 (Thu)	AM	Life Hall (5F)	Electron Optics & Applications 9:00-10:15		Commercial Session 10:35-12:05	Present: Poster Short Photo Group	Break (Hamamatsu Photonics Luncheon Seminar) 12:30-13:50
		Senri Room (6F)		Authors Corner 10:15-10:35	Exhibition 10:00-		
	PM	Life Hall (5F)	Invited Talk 13:50-14:50		Fault Localization I 16:10-17:00	Special Invited Talk 17:20-18:20	Evening Session 18:50-20:50
		Senri Room (6F)		Break 14:50-15:10	Poster Session 15:10-16:10	Exhibition -17:00	Authors Corner 17:00-17:20

13 (Fri)	AM	Life Hall (5F)	Fault Localization II 9:00-10:15		Fault Localization III 10:35-11:50		
		Senri Room (6F)		Authors Corner 10:15-10:35	Exhibition 10:00-	Authors Corner 11:50-12:10	
	PM	Life Hall (5F)	Invited Talk 13:10-14:10		Physical Analysis 14:30-15:45		Panel: Dopant Visualization 16:05-17:35
		Senri Room (6F)		Break 14:10-14:30	Exhibition -17:00	Authors Corner 15:45-16:05	